

Notice of References Cited	Application/Control No. 10/517,206		Applicant(s)/Patent Under Reexamination SHIMAZU ET AL.	
	Examiner John L. Goff		Art Unit 1791	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2002/0016418	02-2002	Maruyama et al.	525/326.6
*	B	US-2001/0033544	10-2001	Tanaka, Mieko	369/283
*	C	US-5,965,269	10-1999	Inada et al.	428/413
*	D	US-5,218,063	06-1993	Kimball, deceased, Michael E.	525/531
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
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	P					
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	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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